Issue Classification

App	plica	tion/	Con	trol	No
-----	-------	-------	-----	------	----

10626358

Examiner /

Devona E Faulk

Art Unit

AOKI ET AL.

Applicant(s)/Patent Under Reexamination

2615

ORIGINAL						INTERNATIONAL CLASSIFICATION									
	CLASS SUBCLASS			1			С	LAIMED		NON-CLAIMED					
700			94			G	0	6	F	17 / 00 (2006.01.01)					
		DOSC DI	FEDENIA	F(C)		н	0	4	В	1 / 00 (2006.01.01)					
	C	KUSS KI	EFERENC	E(3)		G	1	0	н	5 / 00 (2006.01.01)					
CLASS	SU	BCLASS (ONE SUBCL	ASS PER B	LOCK)	G	1	0	н	1 / 08 (2006.01.01)					
381	119					G	1	0	н	7 / 00 (2006.01.01)					
369	4		1	1		G	1	0	н	5 / 02 (2006.01.01)					
84	660	625	602	659	653										
•															
							110						1 10 7		
	ļ					1									
							<u> </u>								
	ļ			<u>.</u>											
		Nah				_									
						-	<u> </u>				_				
	- 	_				\bot	ļ	ļ			ļ	ļ			
	ļ		_	<u> </u>		+	ļ				ļ			_	
	 			_		╁	_		_		ļ	ļ			
		-						_	_						
						—	ļ	_			<u> </u>		_		
	 					+	 		<u> </u>			_	-	-	
	-					+			-		-	-	_	_	
	 					_	-				 	-		<u> </u>	
	 	 				+	\vdash	_			\vdash				
	1					+-					\vdash				
· · · · · ·						+					\vdash		-		-
					1	╅					\vdash		\vdash		
		X E	7	1 - '			571								
	† 					\top		<u> </u>			Н				
	† -							_					_	<u> </u>	
	1							 -		-		-		-	
	 		1	1		\top	 	\vdash			\vdash	\vdash		-	
			<u> </u>			\top	Т	-				一			· -

/Devona E Faulk/ (Assistant Examiner)	3/2/2008 (Date)	Total Claims Allowed: 22					
(Primary Examiner)	VIVIAN CHIN SUPERVISORY PATENT EXAMENER (Date)	O.G. Print Claim(s) 1	O.G. Print Figure				